LEEM 6 PEEM

TRIESTE, ITALY 7-11 SEPTEMBER 2008

LEEM-PEEM is a biennial meeting reviewing the status of LEEM, PEEM, SPLEEM, XPEEM and related techniques. It aims at promoting and disseminating applications of cathode lens microscopy to a broad audience of interested scientists. The workshop will highlight the most recent scientific advances as well as instrumental developments. Topics will cover thin films, steps on surfaces, magnetism, time resolved PEEM/LEEM, surface science, nanostructures, two-photon photoemission, applications of XPEEM in biology, geology and medicine and other subject areas.

Guest Lecturers

Carlo Carbone, *Trieste, Italy*Abdul R. Faruqi, *Cambridge, UK*Eugen E. Krasovskii, *Kiel, Germany*Robert Schlögl, *Berlin, Germany*Darrell G. Schlom, *PA, USA*

International advisory board

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